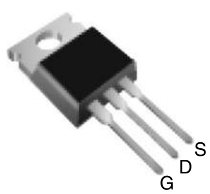
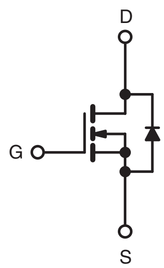
Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	600	
$R_{DS(on)}$ (Ω)	V_{GS} = 10 V	0.385
Q_g (Max.) (nC)	100	
Q_{gs} (nC)	30	
Q_{gd} (nC)	46	
Configuration	Single	

TO-220





N-Channel MOSFET

FEATURES

- Super Fast Body Diode Eliminates the Need for External Diodes in ZVS Applications
- Lower Gate Charge Results in Simpler Drive Requirements
- Enhanced dV/dt Capabilities Offer Improved Ruggedness
- Higher Gate Voltage Threshold Offers Improved Noise Immunity
- Lead (Pb)-free Available

Available
RoHS*
COMPLIANT

APPLICATIONS

- Zero Voltage Switching SMPS
- Telecom and Server Power Supplies
- Uninterruptible Power Supplies
- Motor Control Applications

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRFB16N60LPbF
	SiHFB16N60L-E3
SnPb	IRFB16N60L
	SiHFB16N60L

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V_{DS}	600	V
Gate-Source Voltage			V_{GS}	± 30	
Continuous Drain Current	V_{GS} at 10 V	T_C = 25 °C	I_D	16	A
		T_C = 100 °C		10	
Pulsed Drain Current[a]			I_{DM}	60	
Linear Derating Factor				2.5	W/°C
Single Pulse Avalanche Energy[b]			E_{AS}	310	mJ
Avalanche Current[a]			I_{AR}	16	A
Repetitive Avalanche Energy[a]			E_{AR}	31	mJ
Maximum Power Dissipation	T_C = 25 °C		P_D	310	W
Peak Diode Recovery dV/dt[c]			dV/dt	10	V/ns
Operating Junction and Storage Temperature Range			T_J, T_{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s			300[d]	
Mounting Torque	6-32 or M3 screw			10	lbf · in
				1.1	N · m

Notes

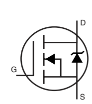
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Starting T_J = 25 °C, L = 2.5 mH, R_G = 25 Ω, I_{AS} =16 A, dV/dt = 10 V/ns (see fig. 12a).
c. $I_{SD} \leq 16$ A, dI/dt ≤ 340 A/µs, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.
d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	°C/W
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.4	

SPECIFICATIONS T_J = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V_{DS}	V_{GS} = 0 V, I_D = 250 µA	600	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25 °C, I_D = 1 mA	-	0.39	-	V/°C
Gate-Source Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = 250 µA	3.0	-	5.0	V
Gate-Source Leakage	I_{GSS}	V_{GS} = ± 30 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 600 V, V_{GS} = 0 V	-	-	50	µA
		V_{DS} = 480 V, V_{GS} = 0 V, T_J = 125 °C	-	-	2.0	mA
Drain-Source On-State Resistance	$R_{DS(on)}$	V_{GS} = 10 V; I_D = 9.0 A[b]	-	0.385	0.460	Ω
Forward Transconductance	g_{fs}	V_{DS} = 50 V, I_D = 9.0 A	8.3	-	-	S
Dynamic						
Input Capacitance	C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1.0 MHz, see fig. 5	-	2720	-	pF
Output Capacitance	C_{oss}		-	26	-	
Reverse Transfer Capacitance	C_{rss}		-	20	-	
Effective Output Capacitance	C_{oss} eff.	V_{GS} = 0 V; V_{DS} = 0 V to 480 V[c]	-	120	-	
Effective Output Capacitance (Energy Related)	C_{oss} eff. (ER)		-	100	-	
Total Gate Charge	Q_g	V_{GS} = 10 V; I_D = 16 A, V_{DS} = 480 V, see fig. 7 and 15[b]	-	-	100	nC
Gate-Source Charge	Q_{gs}		-	-	30	
Gate-Drain Charge	Q_{gd}		-	-	46	
Turn-On Delay Time	$t_{d(on)}$	V_{GS} = 10 V; V_{DD} = 300 V, I_D = 16 A, R_G = 1.8 Ω, see fig. 11a and 11b[b]	-	20	-	ns
Rise Time	t_r		-	44	-	
Turn-Off Delay Time	$t_{d(off)}$		-	28	-	
Fall Time	t_f		-	5.5	-	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode 	-	-	16	A
Pulsed Diode Forward Current[a]	I_{SM}		-	-	60	
Body Diode Voltage	V_{SD}	T_J = 25 °C, I_S = 16 A, V_{GS} = 0 V[b]	-	-	1.5	V
Body Diode Reverse Recovery Time	t_{rr}	T_J = 25 °C, I_F = 16 A, T_J = 125 °C, dI/dt = 100 A/µs[b]	-	130	200	ns
Body Diode Reverse Recovery Time			-	240	360	
Body Diode Reverse Recovery Charge	Q_{rr}	T_J = 25 °C, I_S = 16 A, T_J = 125 °C, dI/dt = 100 A/µs[b]	-	450	670	nC
Body Diode Reverse Recovery Charge			-	1080	1620	
Body Diode Reverse Recovery Current	I_{RRM}	T_J = 25 °C	-	5.8	8.7	A
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.
c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS}.
C_{oss} eff. (ER) is a fixed capacitance that stores the same energy as C_{oss} whil V_{DS} is rising from 0 to 80 % V_{DS}.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

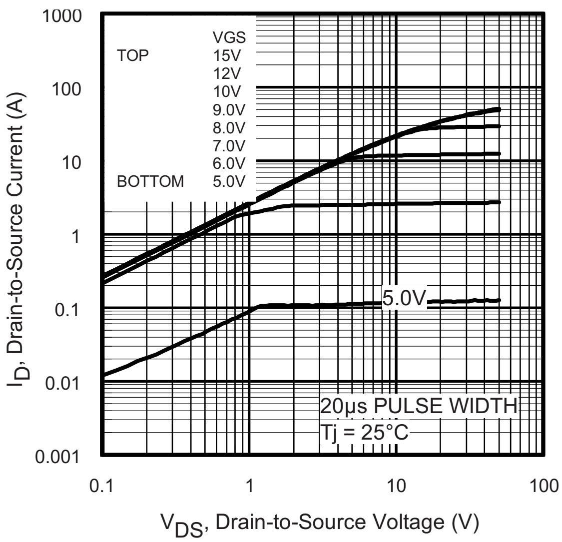


Fig. 1 - Typical Output Characteristics

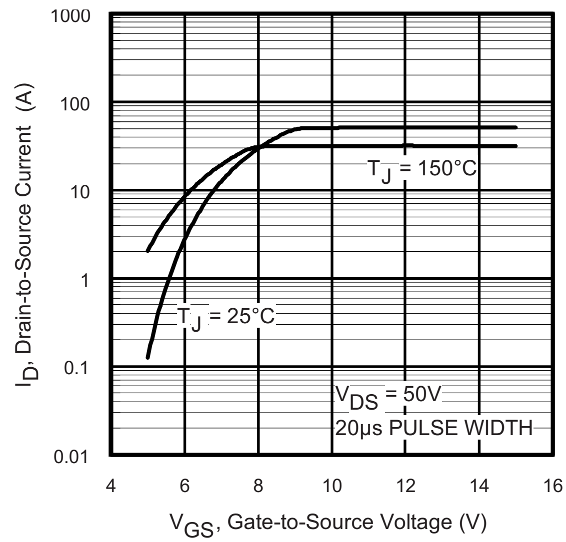


Fig. 3 - Typical Transfer Characteristics

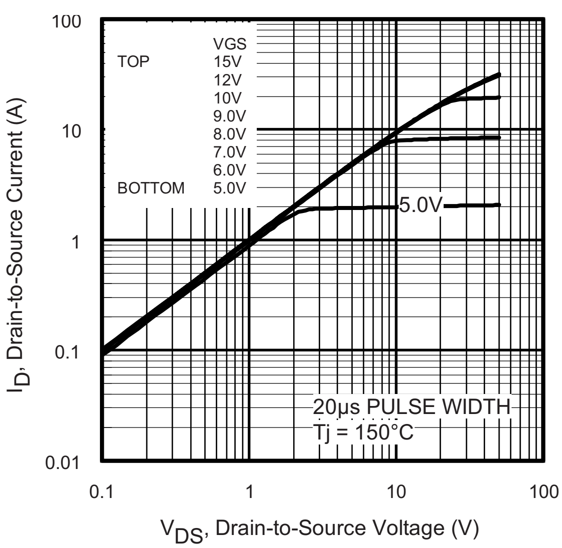


Fig. 2 - Typical Output Characteristics

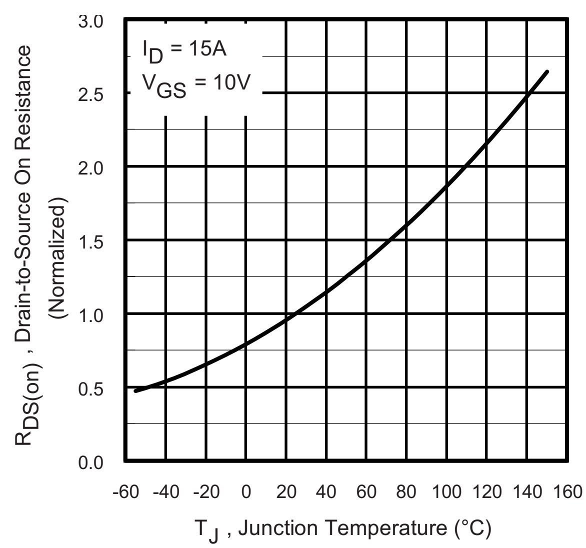


Fig. 4 - Normalized On-Resistance vs. Temperature

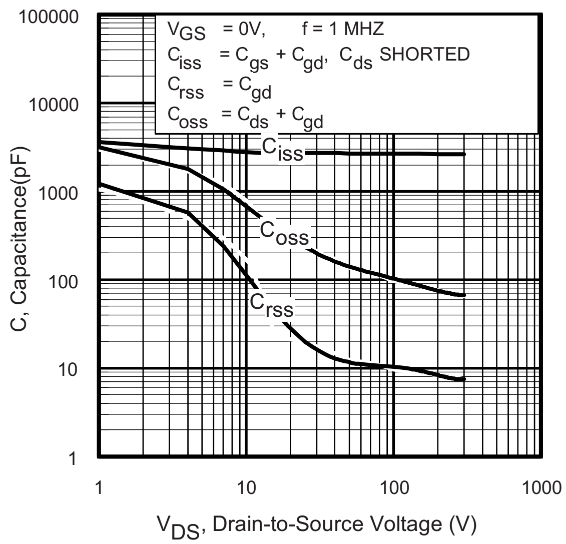


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

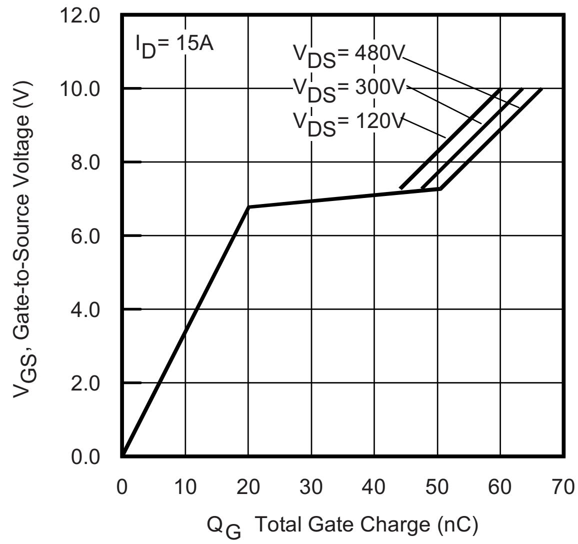


Fig. 7 - Typical Source-Drain Diode Forward Voltage

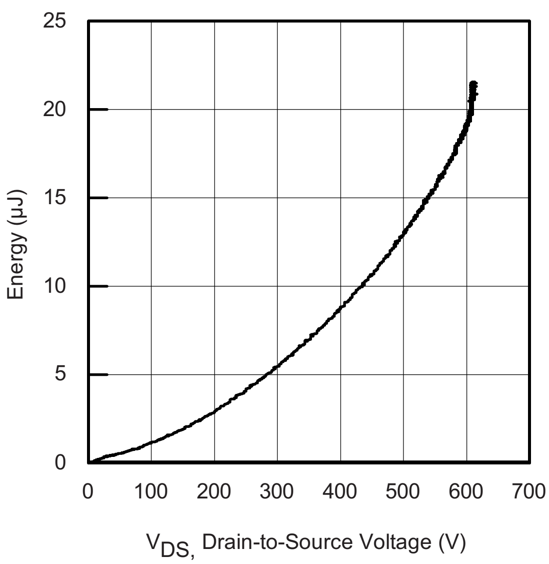


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

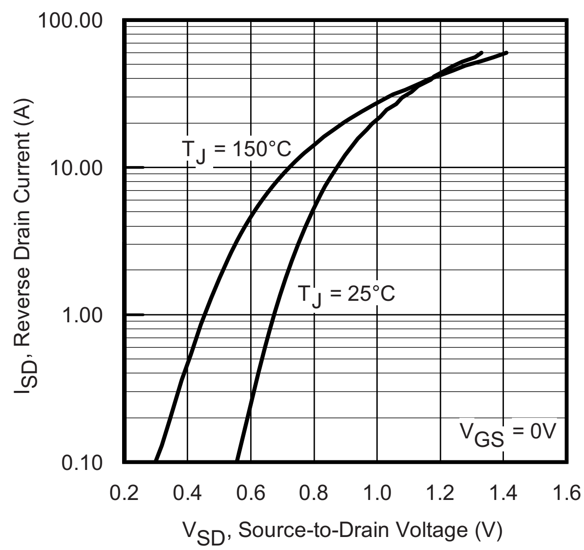


Fig. 8 - Maximum Safe Operating Area

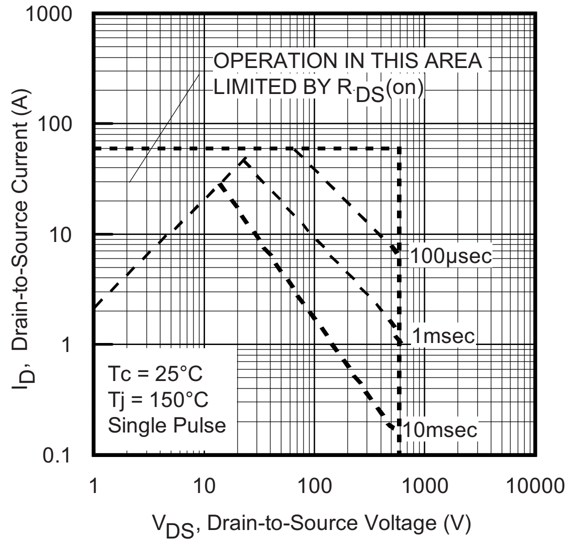


Fig. 9 - Maximum Safe Operating Area

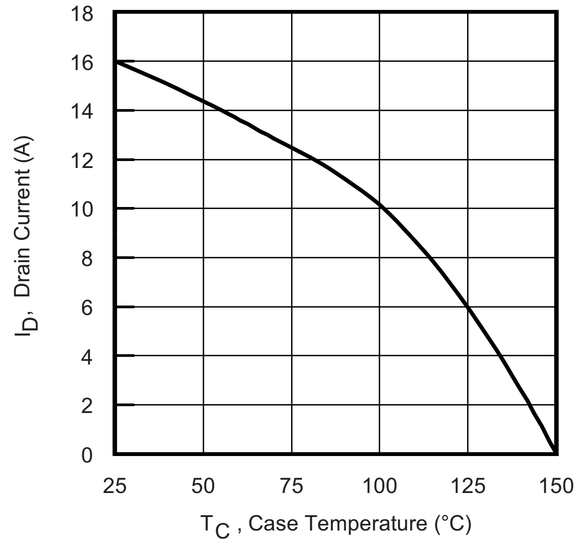


Fig. 10 - Maximum Darin Current vs. Case Temperature

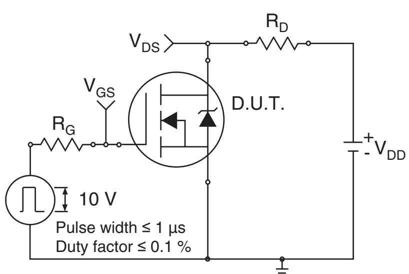


Fig. 11a - Switching Time Test Circuit

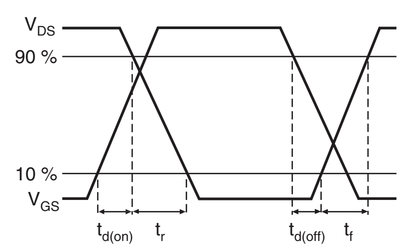


Fig. 11b - Switching Time Waveforms

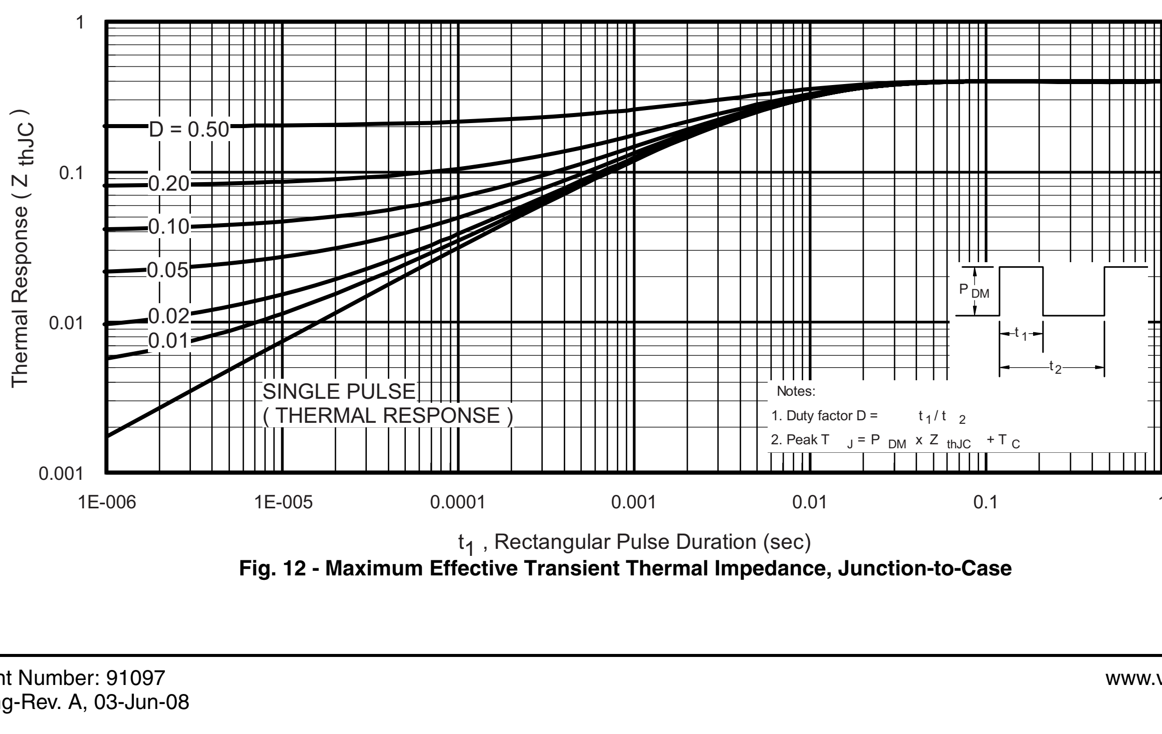


Fig. 12 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

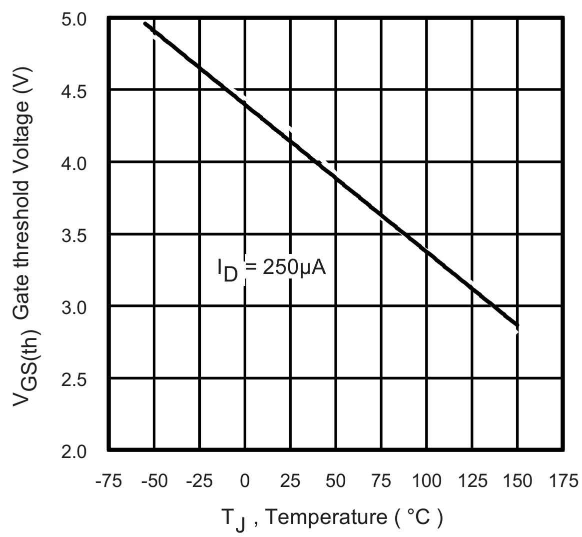


Fig. 13 - Threshold Voltage vs. Temperature

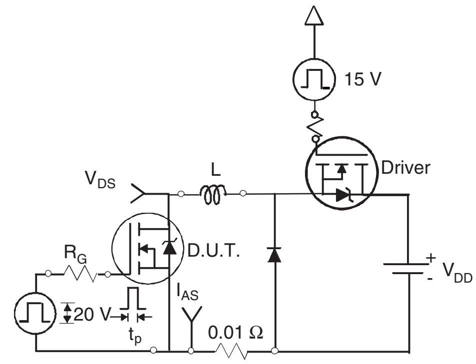


Fig. 14b - Unclamped Inductive Test Circuit

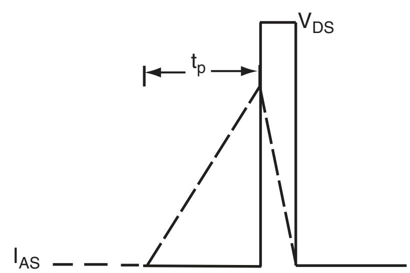


Fig. 14c - Unclamped Inductive Waveforms

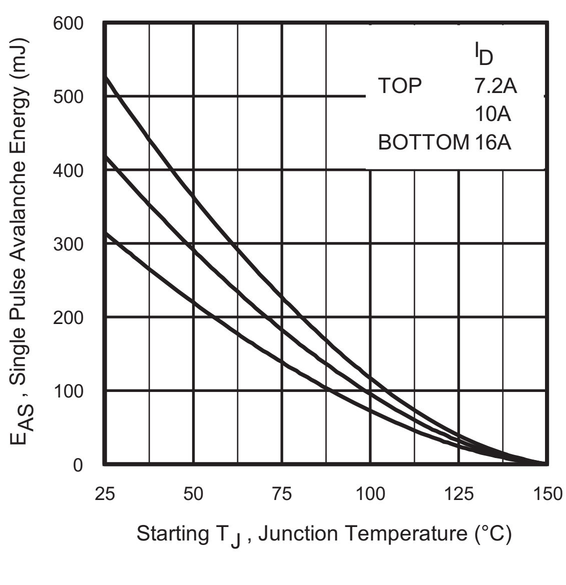


Fig. 14a - Maximum Avalanche Energy vs. Drain Current

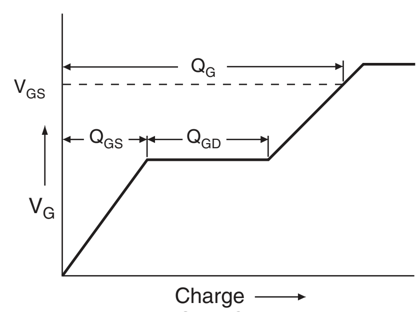


Fig. 15a - Basic Gate Charge Waveform

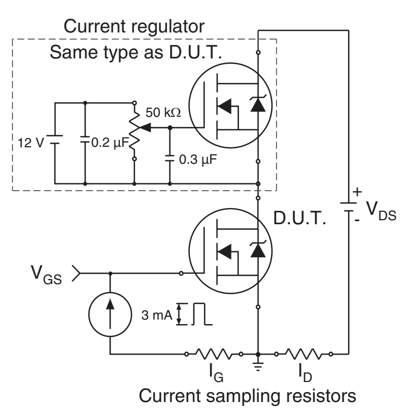
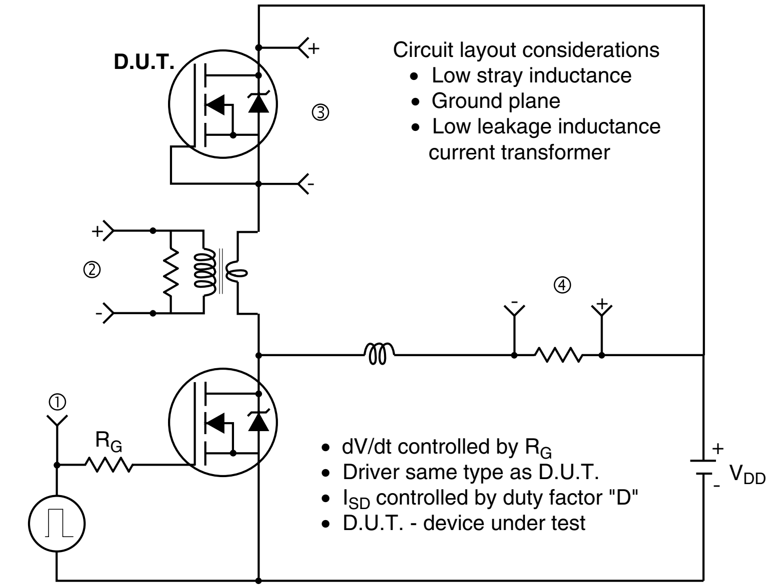
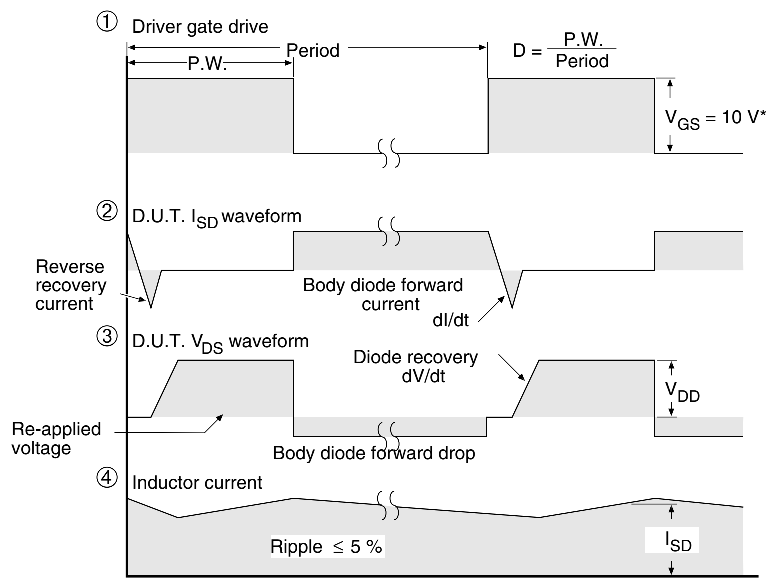


Fig. 15b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit





* V_{GS} = 5 V for logic level devices

Fig. 16 - For N-Channel

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